

In re Patent Application of:
TAILLIET
Serial No. 10/025,372
Filing Date: December 19, 2001

In the Specification:

Please replace the paragraph beginning at page 8, line 9, with the following rewritten paragraph:

~~FIG. 5 is a~~ FIGS. 5A and 5B are schematic block ~~diagram~~
diagrams respectively providing a more detailed view of the
EEPROM programming circuitry ~~including and~~ a circuit for
determining and programming a piece of calibration data according
to the method of the invention;

Please replace the paragraph beginning at page 11, line 17, with the following rewritten paragraph:

The tester may therefore start sending a value only
after a minimum duration (e.g., 2.5 milliseconds) has passed
(FIG. 3a). Below this duration, the integrated circuit is not
adjusted and will be discarded. In the example illustrated in
FIGS. 3a and 3b, the tester then sends the following values: the
first value $K1=2=(5/2.5)$ at ~~t_0~~ $t=2.5$ ms; the second value
 $K2=1.82=(5/2.75)$ at ~~t_0~~ $t=2.75$ ms; ...; and the thirty-first value
 $K31=0.5=(5/10)$ at $t=10$ ms. The calibration table of the tester
then includes thirty-one values.

Please replace the paragraph beginning at page 22, line 27, with the following rewritten paragraph:

Each adjustment arm includes a transistor TB1 connected to the

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node ~~NB~~ NB and series-connected with another transistor Tb1 connected to ground. The transistor TB1 is connected as a diode. The transistor Tb1 is controlled by the corresponding bit of the piece of calibration data KE. Thus, the i-ranking stage Ei includes 2^i adjustment arms (TB1, Tb1), all controlled by the i-ranking data bit k_i of the piece of calibration data KE.